

# 15ECE313/VLSI Design VI Semester Department of ECE Amrita School of Engineering, Bengaluru



# Chapter 7 Electronic Analysis of CMOS Logic Gates



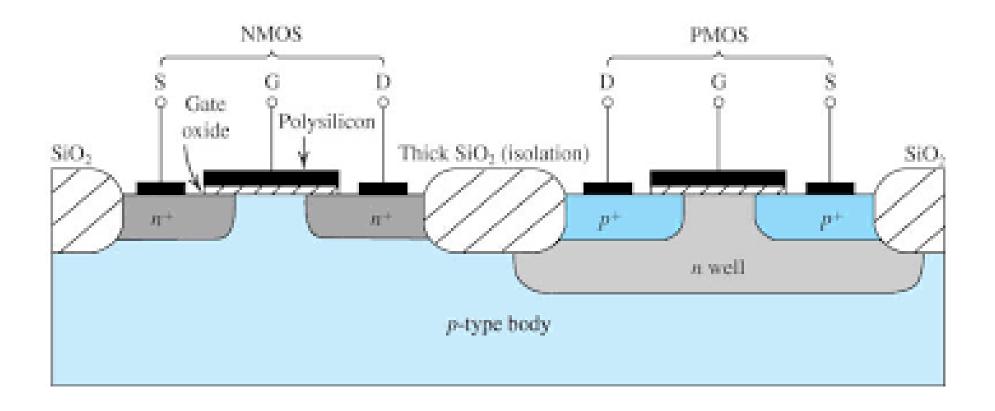
# Chapter 7 Electronic Analysis of CMOS Logic Gates

#### Goal

- Understand how to perform electronic analysis of CMOS logic gates. DC characteristics Noise margin
- Switching characteristics
- Power



# **PMOS** and **NMOS** Structure

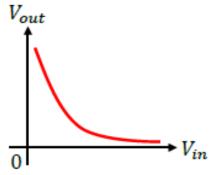


Region		NMOSFET	PMOSFET  SECURIT ON H SITH TO THE ESTABLISHED U/S 3 OF UGC Act 1956		
Cut Off	$V_{GS} < V_{Tn}$	$I_D = 0$	$V_{SG} <  V_{Tp} $	$I_D = 0$	
Linear Region (Resistive)	$V_{GS} > V_{Tn}$ $V_{DS} < V_{GS} - V_{Tn}$	$I_{D} = \mu_{n} c_{ox} \frac{w}{L} \{ (V_{GS} - V_{Tn}) V_{DS} - \frac{1}{2} V_{DS}^{2} \}$	$V_{SG} >  V_{Tp} $ $V_{SD} < V_{SG} -  V_{Tp} $	$I_{D} = \mu_{p} c_{ox} \frac{w}{L} \{ (V_{SG} -  V_{Tp} ) V_{SD} - \frac{1}{2} V_{SD}^{2} \}$	
Saturation Region	$V_{GS} > V_{Tn}$ $V_{DS} \ge V_{GS} - V_{Tn}$	$I_D = \frac{1}{2}\beta_n (V_{GS} - V_{Tn})^2$	$V_{SG} >  V_{Tp} $ $V_{SD} \ge V_{SG} -  V_{Tp} $	$I_D = \frac{1}{2}\beta_p \left(V_{SG} -  V_{Tp} \right)^2$	

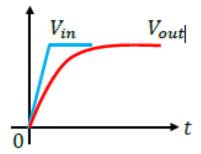
#### **Analysis**



- DC Analysis
  - Vin vs. Vout = Voltage Transfer Characteristic (VTC)



- Transient (switching) analysis
  - Vin(t) vs. Vout(t)



# The CMOS inverter gives the basic for calculating the electrical characteristic of logic gates

- » The conduction states of  $M_n$  and  $M_p$  is determined by input voltage  $V_{in}$
- » Two types of calculations: DC analysis and transient analysis

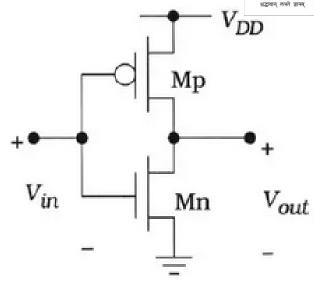
#### DC analysis

» Provide a direct mapping of the input to the output, such that to determine  $V_{out}$ 

#### Transient analysis

» The input voltage is an explicit function of time  $V_{in}(t)$  corresponding to a changing logic value





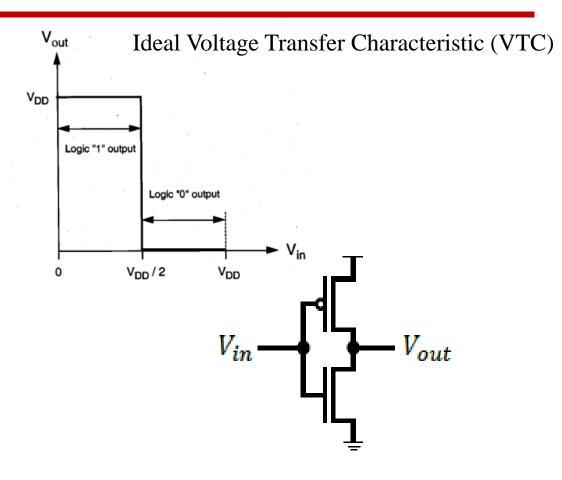
pFET: 
$$V_{Tp} < 0$$
  
 $\beta_p = k'_p \left(\frac{W}{L}\right)_p$ 

nFET: 
$$V_{Tn} > 0$$
  
 $\beta_n = k'_n \left(\frac{W}{L}\right)_n$ 



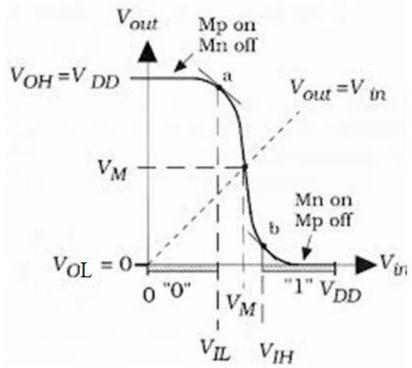
# CMOS Inverter – DC Characteristics

- Logic swing
  - When  $V_{in} = 0$ 
    - $V_{out} = V_{DD}$
    - Output high voltage V<sub>OH</sub> = V<sub>DD</sub>
  - When  $V_{in} = V_{DD}$ 
    - $V_{out} = 0$
    - Output low voltage  $V_{OL} = 0$
  - Logic swing
    - $V_L = V_{OH} V_{OL} = V_{DD}$





#### **CMOS Inverter-VTC**



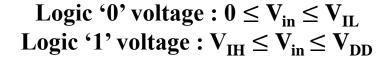
CMOS Inverter Voltage Transfer Characteristic (VTC)

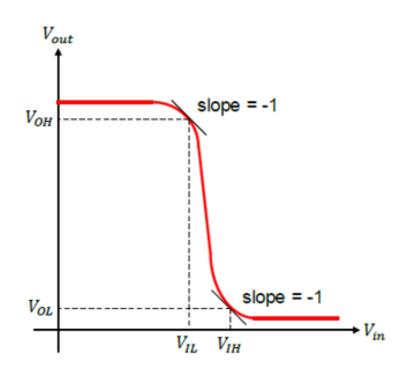
 $V_{IH}$ : Min. high input voltage

 $V_{IL}$ : Max. low input voltage

V<sub>OH</sub>: Min. high output voltage

Vol.: Max. low output voltage

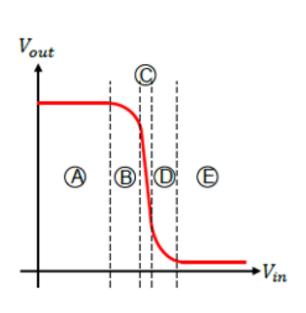




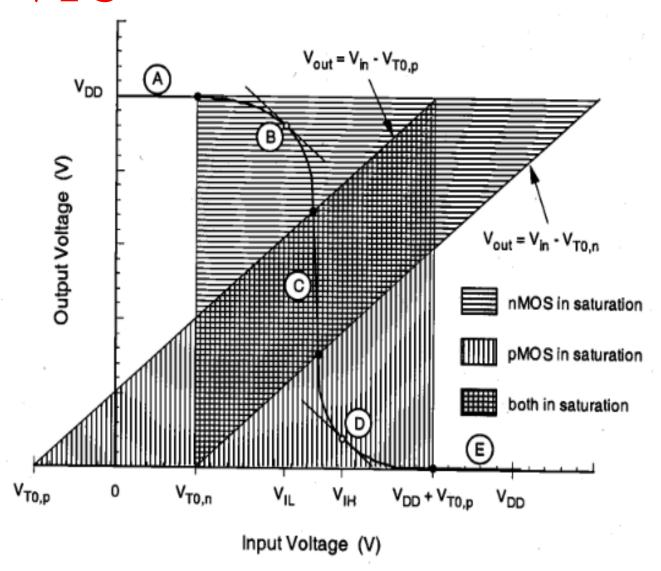
VIL and VIH are the two points at which Slope is equal to (dvout/dvin) = -1

#### **CMOS Inverter-VTC**





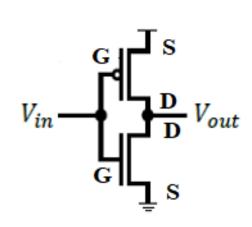
CMOS Inverter Voltage Transfer Characteristic (VTC)



NM.	IOS	PMOS		
Condition	Remark	Condition	Remark	
$V_{GS} > V_{Tn}$	If satisfied then ON otherwise OFF	$V_{SG} >  V_{Tp} $	If satisfied then ON otherwise OFF	
$V_{DS} \ge V_{GS} - V_{Tn}$	If satisfied then Saturation Region otherwise Linear region or Non- saturation region	$V_{SD} \geq V_{SG} -  V_{Tp} $	If satisfied then Saturation Region otherwise Linear region or Non- saturation region	



# Finding Region of Operation of MOSFETs in various regions of VTC of CMOS Inverter



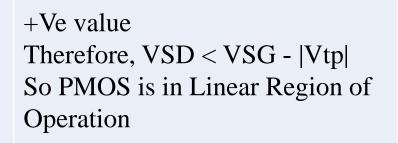
Region	Vin	Vout	NMOS Operating Region	PMOS Operating Region			
A	< Vtn	VDD					
В	VIL	$VOH \approx VDD$ (HIGH)					
C	VM	VM					
D	VIH	$VOL \approx GND$ (LOW)					
Е	VDD	GND					
/// CLD! ///	// CL Design V// Consenter Description of ECE						

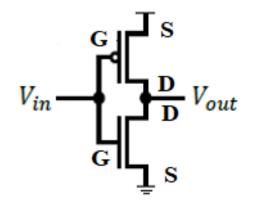
	For	Region	ı A (	on V	/TC
<b>T</b> O 0				DI	<b>*</b>



For NMOS	For PMOS
$VG = (\langle Vtn \rangle)$	$VG = (\langle Vtn \rangle)$
VS = 0	VS = VDD
$VGS = VG - VS = (\langle Vtn \rangle) - 0$	VSG = VS - VG = VDD -
= $<$ $Vtn$	$($
Therefore, VGS < Vtn	Therefore, $VSG >  Vtp $
	Therefore, PMOS is ON
Therefore, NMOS is OFF	To find the region of operation,
	VSD = VS - VD = VDD - VDD
	=0
	VSG -  Vtp  = VS - VG -  Vtp  =
	$VDD - (\langle Vtn \rangle -  Vtp )$
	(\vii) -   v ip

Region	Vin	Vout	NMOS Operating Region	PMOS Operating Region
A	< Vtn	VDD		
В	VIL	$VOH \approx VDD$ $(HIGH)$		
C	VM	VM		
D	VIH	$VOL \approx GND$ (LOW)		
Е	VDD	GND		







# **CMOS Inverter-VTC Region of Operation for MOSFETs**

Region	Vin	Vout	NMOS Operating Region	PMOS Operating Region
A	< Vtn	VDD	Cut Off	Linear
В	VIL	$VOH \approx VDD$ (HIGH)	Saturation	Linear
C	VM	VM	Saturation	Saturation
D	VIH	$VOL \approx GND$ (LOW)	Linear	Saturation
E	VDD	GND	Linear	Cut off

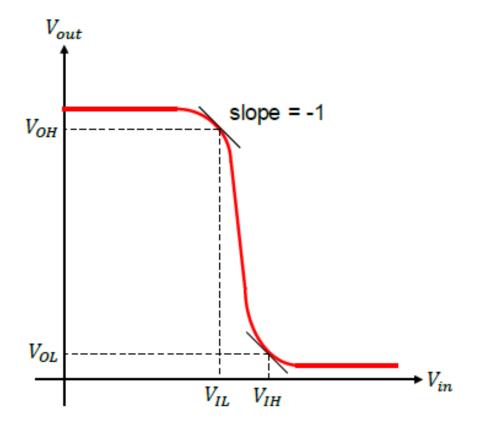
#### **CMOS Inverter – DC Characteristics**



- Voltage noise margin
  - $-VNM_H = V_{OH} V_{IH}$
  - $VNM_L = V_{IL} V_{OL}$

The noise margins give a quantitative measure of how stable the inputs are with respect to coupled electromagnetic signal interference.

- V<sub>IH</sub>: Min. high input voltage
- V<sub>IL</sub>: Max. low input voltage
- V<sub>OH</sub>: Min. high output voltage
- V<sub>OL</sub>: Max. low output voltage





# Calculation of Mid Point Voltage V<sub>M</sub>

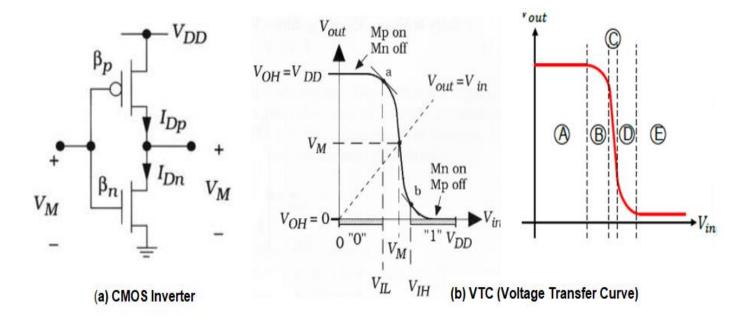
- Switching threshold- Point on VTC where Vout = Vin is called *midpoint voltage*.
- At midpoint voltage Vin = Vout = V<sub>M</sub>
- Point is found in C region of VTC
- In this C region, both NMOS and PMOS are ON and found to be getting operated in Saturation region of operation.

#### For nFET

$$\begin{split} &V_{GSn} = V_G - V_S = V_{in} \text{ - } V_S = V_M \\ &V_{DSn} = V_D - V_s = V_{out} \text{ - } V_S = V_M \\ &V_M > (V_M - V_{Tn}) \\ &So\ V_{DSn} > (V_{GSn} - V_{Tn}) \end{split}$$

#### For pFET

$$\begin{split} &V_{SGp}\!=V_S-V_G=V_{DD}\text{-}V_M\\ &V_{SDp}=V_S-V_D=V_{DD}\text{-}V_M\\ &So\ V_{SDp}\!>\!(V_{SGp}\text{-}|V_{Tp}|) \end{split}$$





# **Calculation of Mid Point Voltage V<sub>M</sub>**

• In an Inverter

$$I_{Dn} = I_{Dp}$$

Solve equation for  $V_{M}$ 

$$I_{Dn} = \frac{\beta_n}{2} (V_{GSn} - V_{tn})^2 = \frac{\beta_p}{2} (V_{SGp} - |V_{tp}|)^2 = I_{Dp}$$

- express in terms of  $V_M$ 

$$\frac{\beta_n}{2}(V_M - V_{tn})^2 = \frac{\beta_p}{2}(V_{DD} - V_M - |V_{tp}|)^2 \implies \sqrt{\frac{\beta_n}{\beta_p}}(V_M - V_{tn}) = V_{DD} - V_M - |V_{tp}|$$

- solve for  $V_M = \frac{VDD - \left|V_{tp}\right| + V_{tn} \sqrt{\frac{\beta_n}{\beta_p}}}{1 + \sqrt{\frac{\beta_n}{\beta_p}}}$ 

$$V_{M} = \frac{VDD - \left|V_{tp}\right| + V_{tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + \sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$

The equation shows that  $V_M$  is set by the nFET-to-pFET ratio

$$\frac{\beta_n}{\beta_p} = \frac{k'_n \left(\frac{W}{L}\right)_n}{k'_p \left(\frac{W}{L}\right)_n}$$



# Calculation of Mid Point Voltage $V_{\rm M}$

• If nFET and pFET are of same size then

$$(W/L)_n = (W/L)_p$$
  
 $C_{OXn} = C_{OXp}$  (always)

$$\frac{\beta_n}{\beta_p} = \frac{\mu_n C_{oxn} \left(\frac{W}{L}\right)_n}{\mu_p C_{oxp} \left(\frac{W}{L}\right)_p} = \frac{\mu_n}{\mu_p} \cong 2or3$$

$$\frac{k'_n}{k'_p} = \frac{\mu_n}{\mu_p} = r = \text{mobility ratio}$$



# **Symmetrical Inverter**

- A symmetrical inverter VTC is one that has equal "0" and "1" input voltage ranges.
- This can be achieved by choosing

$$V_{\rm M} = \frac{1}{2} V_{\rm DD}$$

We know  $I_{Dn} = I_{Dp}$ 

$$\frac{\beta_n}{2}(V_M - V_{tn})^2 = \frac{\beta_p}{2}(V_{DD} - V_M - |V_{tp}|)^2$$

After substituting  $V_{\text{M}} = \frac{1}{2} V_{\text{DD}}$ 

$$\frac{\beta_n}{\beta_p} = \frac{\left(\frac{1}{2}V_{DD-} |V_{Tp}|\right)^2}{\left(\frac{1}{2}V_{DD-} V_{Tn}\right)^2}$$
If  $V_{Tn} = |V_{Tp}|$ 

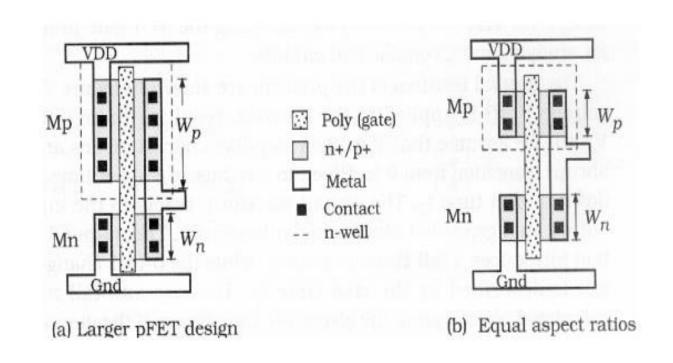
Then 
$$\beta_n = \beta_p$$

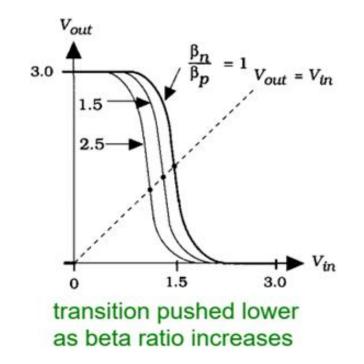
$$\mu_n C_{oxn} \left( \frac{W}{L} \right)_n = \mu_p C_{oxp} \left( \frac{W}{L} \right)_p$$

$$\left(\frac{w}{L}\right)_p = r\left(\frac{w}{L}\right)_n$$



# Dependence of $V_M$ on Device Ratio





$$V_{M} = \frac{VDD - \left|V_{tp}\right| + V_{tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + \sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$



# Solved Problem

# Example 7.1 Consider a CMOS process with the following parameters-

$$k'_n = 140 \,\mu\text{A/V}^2$$
,  $V_{Tn} = 0.70 \,\text{V}$ ,  $k'_p = 60 \,\mu\text{A/V}^2$ ,  $V_{Tp} = -0.7 \,\text{V}$ ,  $V_{DD} = 3.0 \,\text{V}$ . Find-

- (a) The relative sizes of nFET and pFET for symmetrical inverter.
- (b) Midpoint voltage for the inverter with same aspect ratio.

#### Solution:

Consider the case where  $\beta_n = \beta_p$ . We can verify that this is a symmetrical design by calculating

$$V_M = \frac{3 - 0.7 + \sqrt{1}(0.7)}{1 + \sqrt{1}} = 1.5 \text{ V}$$

so that  $V_M$  is one-half the value of the power supply voltage. To achieve this design, we must choose the device aspect ratios such that

$$\frac{\beta_n}{\beta_p} = \frac{k'_n \left(\frac{W}{L}\right)_n}{k'_p \left(\frac{W}{L}\right)_p} = 1$$

where we recall that the process transconductance parameters k' are given by  $k' = \mu_n C_{ox}$ , and are set by the processing. For the present case, we rearrange the expression to read

$$\left(\frac{W}{L}\right)_{p} = \frac{k'_{n}}{k'_{p}} \left(\frac{W}{L}\right)_{n}$$

so that

$$\left(\frac{W}{L}\right)_p = \left(\frac{140}{60}\right)\left(\frac{W}{L}\right)_n = 2.33\left(\frac{W}{L}\right)_n$$

This shows that the pFET must be about 2.33 times larger than the nFET. Let us now examine the case where the nFET and the pFET have the same aspect ratio:  $(W/L)_n = (W/L)_p$ . With the values provided in the problem statement,

$$\frac{\beta_n}{\beta_p} = \frac{k'_n}{k'_p} = 2.33$$

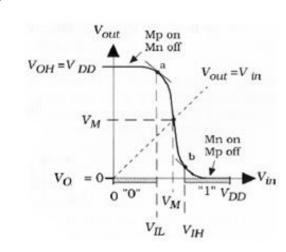
so that the midpoint voltage is given by

$$V_M = \frac{3 - 0.7 + \sqrt{2.33} \quad (0.7)}{1 + \sqrt{2.33}} = 1.33 \text{ V}$$

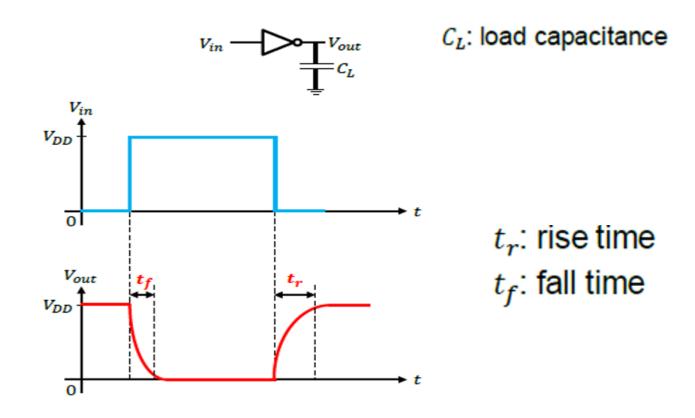


# **Assignment 1**

- 1. A CMOS inverter is built in a process where  $k'_n = 100 \mu A/V^2$ ,  $V_{Tn} = 0.70 \text{ V}$ ,  $k'_p = 42 \mu A/V^2$ ,  $V_{Tp} = -0.8 \text{ V}$ ,  $V_{DD} = 3.3 \text{ V}$ . Find the midpoint voltage if  $(W/L)_n = 10$  and  $(W/L)_p = 14$ . (1.48 V)
- 2. Find the ratio  $(\beta_n/\beta_p)$  needed to obtain an inverter midpoint voltage of 1.3 V with a power supply of 3 V. Assume that  $V_{Tn}=0.60$  V and  $V_{Tp}=-0.82$  V. What would be the relative device sizes if  $k'_n=110 \,\mu\text{A/V}^2$  and the mobility values are related by  $\mu_n=2.2\,\mu_p$ ? (1.58, (W/L)p=1.39(W/L)n)
- 3. State whether the following statements are true or false for the VTC of CMOS inverter shown in figure. (Give proper explanations, prove the statement if necessary).
  - a). The mid-point voltage(V<sub>M</sub>) depends on the threshold voltage of PMOS and NMOS transistors.
  - b). At V<sub>M</sub> both the transistors are in triode region.
  - c). Increasing the threshold voltage of NMOS would decrease the voltage noise margin  $(V_{NML} = V_{IL} V_{OL}).$
  - d). Increasing the size (W/L) of PMOS would move the midpoint voltage upwards.
  - e). For a symmetrical inverter, which has equal "0" and "1" input voltage ranges,  $V_M = 0.5 \ V_{DD}$

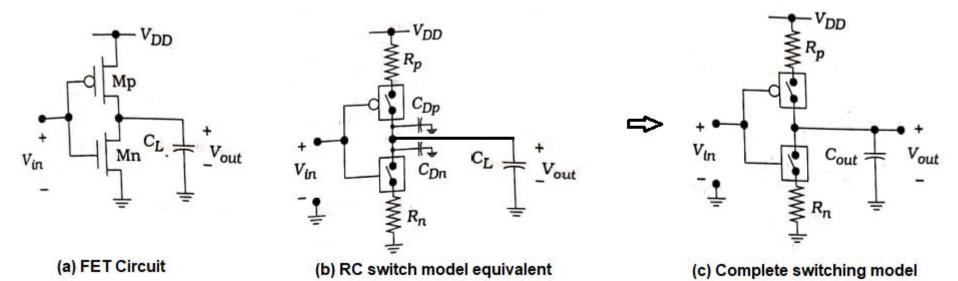








• The rise and fall time delays are due to the parasitic resistance and capacitances of the transistors.



CFET: FET capacitance

$$\begin{array}{l} - \ \, C_{FET} = C_{Dn} + C_{Dp} \\ \ \, \times \ \, C_{Dn} = C_{GSn} + C_{DBn} = \frac{1}{2} C_{ox} L' W_n + C_{Jn} A_n + C_{Jswn} P_n \\ \ \, \times \ \, C_{Dp} = C_{GSp} + C_{DBp} = \frac{1}{2} C_{ox} L' W_p + C_{Jp} A_p + C_{Jswp} P_p \end{array}$$

C<sub>L</sub>: load capacitance

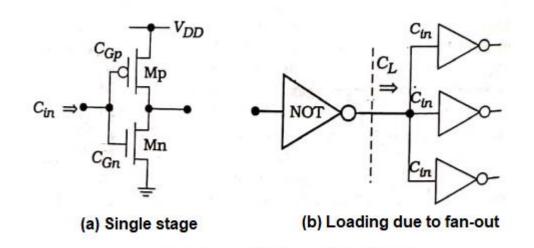
Cout: total output capacitance

$$-C_{out} = C_{FET} + C_L$$



#### Load capacitance c<sub>L</sub>

- In a logic chain, every logic gate must drive another or set of logic gates which is known as fan-out of the circuit.
- The fan-out gates act as a load to the driving circuit because of their input capacitance.



Input capacitance and load effects

$$C_{ln} = C_{Gp} + C_{Gn}$$
 Where  $C_G = C_{OX}WL^2$ 

$$C_L = 3C_{ln}$$

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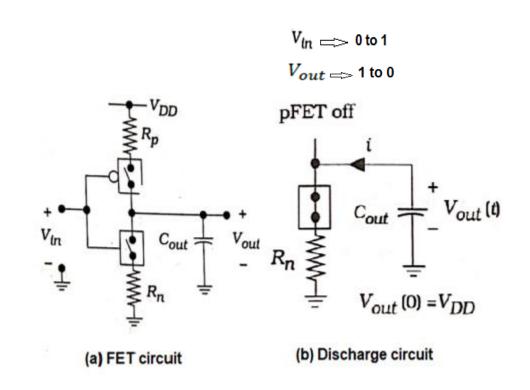
#### Fall time

- From 
$$V_{out} = 0.9V_{DD}$$
 to  $V_{out} = 0.1V_{DD}$ 

- Fall time calculation
  - Discharging (Natural response)

$$- i = -C_{out} \frac{dV_{out}}{dt} = \frac{V_{out}}{R_n}$$

$$\cdot R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})}$$





$$In \left( \begin{array}{c} \text{Voul} (t) \\ \text{VDD} \end{array} \right) = -t/\ln \text{Coul}$$

$$-t/\ln \text{Coul}$$

$$Vout(t) = e$$

$$Vout(t) = V_{DD}e^{-\frac{t}{\tau_n}}$$

$$\cdot \tau_n = R_n C_{out} \text{ (time constant)}$$

$$-t = t_n \ln \left( \frac{V_{DD}}{V_{out}} \right)$$

$$t_f = t_y \cdot t_x$$

$$-t_f = t(V_{out} = 0.1V_{DD}) - t(V_{out} = 0.9V_{DD}) = \tau_n \left( \ln 10 - \ln \frac{10}{9} \right) = \tau_n \ln 9$$

$$-t_f \approx 2.2\tau_n = 2.2 R_n C_{out} \approx 2.2R_n (C_{FET} + C_L) = t_{f0} + 2.2R_n C_L$$

$$-t_{HL} = t_f$$

t<sub>HL</sub>: high-to-low time

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## **CMOS Inverter Transient(Switching) Characteristics-**

- Rise time
  - From  $V_{out} = 0.1V_{DD}$  to  $V_{out} = 0.9V_{DD}$
- Rise time calculation
  - Charging (Step response)

$$- i = C_{out} \frac{dV_{out}}{dt} = \frac{V_{DD} - V_{out}}{R_p}$$

• 
$$R_p = \frac{1}{\beta_p(V_{DD} - |V_{Tp}|)}$$

- 
$$V_{out}(t) = V_{DD} \left(1 - e^{-\frac{t}{\tau_p}}\right)$$
  
•  $\tau_p = R_p C_{out}$  (time constant)

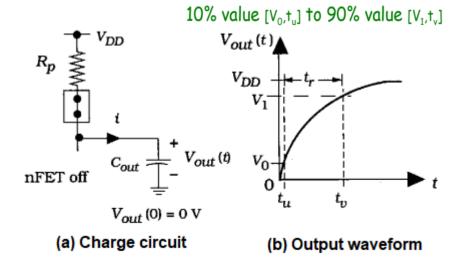
$$- t = \tau_p \ln \left( \frac{v_{DD}}{v_{DD} - v_{out}} \right)$$

- 
$$t_r = t(V_{out} = 0.9V_{DD}) - t(V_{out} = 0.1V_{DD}) = \tau_p \left(\ln 10 - \ln \frac{10}{9}\right) = \tau_p \ln 9$$

$$-t_r \approx 2.2\tau_p \approx 2.2 R_p C_{out} \approx 2.2 R_p (C_{FET} + C_L) = t_{r0} + 2.2 R_p C_L$$

$$- t_{LH} = t_r$$

t<sub>LH</sub>: low-to-high time



Rise time calculatiom



#### Maximum Signal Frequency

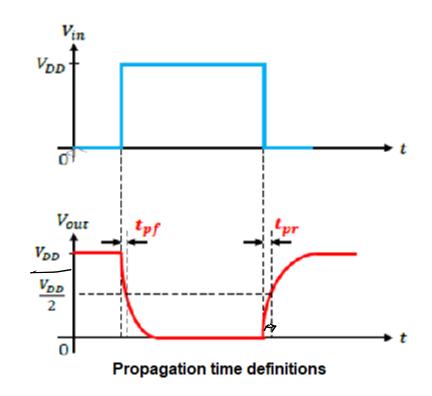
This is the largest frequency that can be applied to the gate and still allow the output to settle to a definable state.

$$f_{max} = \frac{1}{t_{HL} + t_{LH}} = \frac{1}{t_f + t_r} = \frac{1}{2.2 (\tau_n + \tau_p)}$$

#### • The Propagation Delay

> Reaction time delay from input to output

- 
$$t_p = \frac{t_{pf} + t_{pr}}{2}$$
  
•  $t_{pf}$ : output fall time  $(V_{DD} \rightarrow \frac{V_{DD}}{2})$   
-  $t_{pf} = \tau_n \ln 2$   
•  $t_{pr}$ : output rise time  $(0 \rightarrow \frac{V_{DD}}{2})$   
-  $t_{pr} = \tau_p \ln 2$ 

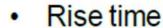




## **CMOS Inverter-General Analysis**

#### Output capacitance

$$- C_{out} = C_{FET} + C_L$$



- 
$$t_r = \tau_p \ln 9 \approx 2.2 R_p (C_{FET} + C_L) = t_{r0} + 2.2 R_p C_L$$
  
•  $R_p = \frac{1}{\beta_p (V_{DD} - |V_{Tp}|)}$ 

 $C_{FET} = C_{Dn} + C_{Dp}$ 

 $C_{Dn} = C_{GSn} + C_{DBn} = \frac{1}{2}C_{ox}L'W_n + C_{Jn}A_n + C_{Jswn}P_n$   $C_{Dp} = C_{GSp} + C_{DBp} = \frac{1}{2}C_{ox}L'W_p + C_{Jp}A_p + C_{Jswp}P_p$ 

Fall time

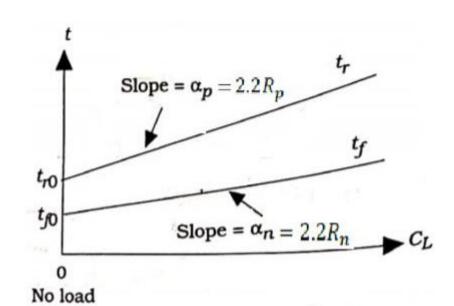
- 
$$t_f = \tau_n \ln 9 \approx 2.2 R_n (C_{FET} + C_L) = t_{f0} + 2.2 R_n C_L$$
  
•  $R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})}$ 

Speed vs. area

$$-\beta\uparrow \Rightarrow R\downarrow \Rightarrow t\downarrow$$

· Area goes up, but the logic is faster.

----Fast circuits consume more area than slow circuits ---



General behavior of the rise and fall times





#### Normal CMOS Inverter

If 
$$\left(\frac{w}{L}\right)_n = \left(\frac{w}{L}\right)_p$$
  
 $\beta_n > \beta_p$  (since  $\mu_n > \mu_p$ )  
 $R_n < R_p$  ( $R \alpha \frac{1}{\beta}$ )  
So  $t_r > t_f$  ( $t_r \alpha R_p$  and  $t_f \alpha R_n$ )

$$R_p = \frac{1}{\beta_p(V_{DD} - |V_{Tp}|)}$$

$$R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})}$$

#### For Symmetrical Inverter

If 
$$\beta_n = \beta_p$$

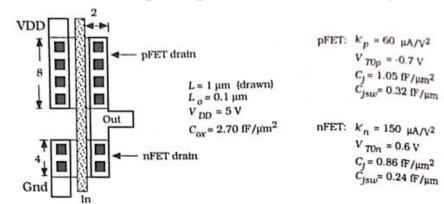
$$\left(\frac{w}{L}\right)_p = r\left(\frac{w}{L}\right)_n \quad \text{where } r = \frac{\mu_n}{\mu_p}$$
If  $V_{Tn} = |V_{Tp}|$ 

$$R_n = R_p$$
So  $t_r = t_f$ 

#### **Solved Problems**



**Example 7.2**. Find the output capacitance in the NOT gate shown in Figure.



#### Solution.

First we will find the gate capacitances using

$$C_{Gp} = (2.70)(1)(8) = 21.6 \text{ fF} = C_{OX} W_p L'$$
  
 $C_{Gn} = (2.70)(1)(4) = 10.8 \text{ fF} = C_{OX} W_n L'$ 

Next, note that the overlap distance  $L_o$  is specified as 0.1  $\mu$ m, which should be included in the area and perimeter factors in the junction capacitances. For the pFET, the p+ capacitance is

$$C_p = C_j A_{bot} + C_{jsw} P_{sw}$$

SO

$$C_p = (1.05)(8)(2.1) + (0.32)2(8 + 2.1) = 24.10 \text{ fF}$$

The total capacitance at the pFET drain is therefore given by

$$C_{Dp} = \frac{21.6}{2} + 24.10 = 34.9 \text{ fF}$$

The nFET drain is analyzed using the same approach. The n+ junction capacitance is

$$C_n = (0.86)(4)(2.1) + (0.24)(2)(4 + 2.1) = 10.15 \text{ fF}$$

so that

$$C_{Dn} = \frac{10.8}{2} + 10.15 = 15.55 \text{ fF}$$

is the total capacitance at the drain of the nFET. Adding gives

$$C_{FET} = C_{Dp} + C_{Dn}$$
  
= 34.9 + 15.55  
= 50.45 fF

as the total internal FET capacitance. The total capacitance at the output is

$$C_{out} = 50.45 + C_{t}$$

in fF, where  $C_L$  is the external load (also in fF).

#### **Solved Problems**



**Example 7.3**. Consider an inverter circuit that has FET aspect ratio of  $(W/L)_n = 6$  and  $(W/L)_p = 8$  in a process where  $k'_n = 150 \,\mu\text{A/V}^2$ ,  $V_{Tn} = 0.7 \,\text{V}$ ,  $k'_p = 62 \,\mu\text{A/V}^2$ ,  $V_{Tp} = -0.85 \,\text{V}$ ,  $V_{DD} = 3.3 \,\text{V}$ . The total output capacitance is estimated to be  $C_{out} = 150 \,\text{fF}$ . Compute rise time, fall time and maximum signal frequency.

Solution:

Consider first the fall time. The pFET resistance is given by

$$R_p = \frac{1}{\beta_p(V_{DD} - |V_{Tp}|)}$$

$$= \frac{1}{(62 \times 10^{-6})(8)(3.3 - 0.85)}$$

$$= 822.9 \Omega$$

The time constant for the charging event is computed using the RC product  $R_pC_{out}$  to find

$$\tau_p = (822.9)(150 \times 10^{-15}) = 123.43$$
 ps

where 1 ps (picosecond) is 10<sup>-12</sup> sec. The rise time is

$$t_r = 2.2\tau_p = 271.55$$
 ps

The fall time is calculated in a similar manner. First, we find the nFET resistance

$$R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})}$$

$$= \frac{1}{(150 \times 10^{-6})(6)(3.3 - 0.70)}$$

$$= 427.35 \Omega$$

so that the discharge time constant is

$$\tau_{\mathbf{n}} = (427.35)(150 \times 10^{-15}) = 64.1$$
 ps

The fall time is

$$t_f = 2.2\tau_n = 141.0$$
 ps

Combining these results, the maximum signal frequency is  $f_{max} = \frac{1}{t_r + t_f} = \frac{1}{271.55 + 141.0 \times 10^{-12}} = 2.42 \text{ GHz}$ 

# **Assignment 2**



- 1. An inverter uses FETs with  $\beta_n = 2.1$  mA/V² and  $\beta_p = 1.8$  mA/V². The threshold voltages are given as  $V_{tn} = 0.6$  V and  $V_{tp} = -0.7$ V and the power supply has a value of  $V_{DD} = 5$  V. The parasitic FET capacitance at the output node is estimated as  $C_{FET} = 74$  fF.
- (a) Find the midpoint voltage. (2.378 V)
- (b) Find the values of  $R_n$  and  $R_p$ . (108.23 ohm, 129.2 ohm)
- (a) Calculate the rise time and fall times at the output when  $C_L = 0$ . (21.03ps, 17.62ps)
- (b) Calculate the rise time and fall time when an external load of value  $C_L = 115$  fF is connected to the output. (53.72ps, 45ps)
- (e) Plot rise time and fall time as functions of C<sub>L</sub>
- 2. A CMOS inverter is designed with  $\beta p = 80 \mu A/V^2$ ,  $\beta n = 0.25 \text{ mA/V}^2$ ,  $V_{tn} = |V_{tp}| = 0.5 \text{ V}$  and VDD = 2.5 V. The total capacitance at the output is 50fF.
- (a) Using general expression for MOSFET resistance in saturation, what is the resistance for each transistor?  $(R_n = 2 \text{ Kohm}, R_p = 6.25 \text{ Kohm})$
- (b) What is the rise time of this circuit? (685.5ps)
- (c) What is the fall time of this circuit? (220ps)
- (d) What is the high-to-low propagation delay for this inverter? (69.3ps)
- (e) What is the low-to-high propagation delay for this inverter? (217ps)
- 3. Consider the NOT gate shown in figure of example 1 when an external load of  $C_L = 80 \text{fF}$  is connected to the output. The electrical channel length is  $L = 0.8 \mu \text{m}$ .
- (a) Find the input capacitance of the circuit. (32.4 fF) Hint:  $C_{ln} = C_{Gp} + C_{Gn}$  Where  $C_G = C_{OX}WL'$
- (b) Find the values of  $R_n$  and  $R_p$ . (303.03 ohm, 387.6 ohm)
- (c) Calculate rise and fall times for the inverter. (111.24ps, 87.04ps)



#### **CMOS Inverter- Power Dissipation**

• The current I<sub>DD</sub> flowing from power supply to ground gives a dissipated power of-

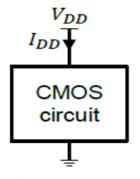
$$P = V_{DD}I_{DD}$$

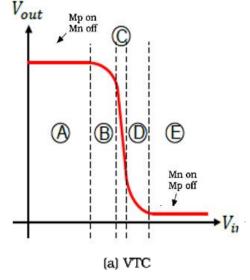
• The current is divided into DC and dynamic contributions so

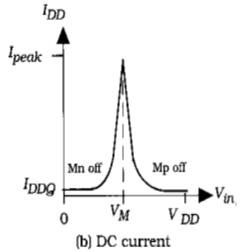
$$P = P_{DC} + P_{dyn}$$

#### **DC Power P**<sub>DC</sub> (Static power) –

- When the input voltage  $V_{in}$  stable at logic "0" or logic "1".
- Region A, E: I<sub>DD</sub> = 0
  - Actually, there is leakage current I<sub>DDQ</sub>.
    - » I<sub>DDO</sub>: quiescent leakage current
  - $P_{DC} = V_{DD}I_{DDQ}$











(c) Discharge

#### **Dynamic Power Dissipation P**<sub>dvn</sub> (Switching Power)-

- When the input is switching the **power dissipated** is called **dynamic power dissipation**.
- A complete cycle of input voltage effectively creates a path for the current to flow from the power supply to the ground.
- During the first half cycle of input voltage-
- ➤ Stored electric charge on the capacitor

$$Q_e = C_{out} V_{DD}$$

- During the second half cycle same amount of charge is lost.
- The average power dissipated over a single cycle, of input voltage  $V_{in}$ , with a period T is-

$$P_{av} = V_{DD}I_{DD} = V_{DD} (Q_e/T)$$
  
 $P_{dyn} = C_{out} V_{DD}^2 f$  where f = 1/T

#### Total power

$$P = V_{DD}I_{DDQ} + C_{out}V_{DD}^2$$
 Power increases with Cout and frequency, and strongly with VDD

(a) Input voltage

(b) Charge

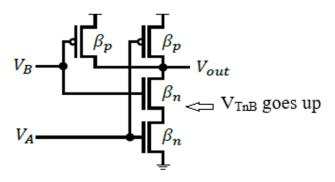
"A fast circuit dissipates more power than a slow circuit"

## **DC Characteristics – NAND Gate**

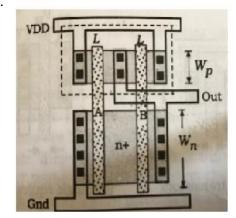


#### • NAND Analysis

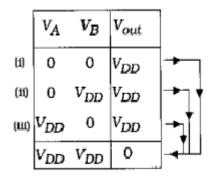
 $\triangleright$  Both the pFETs are described by  $\beta_p$  and both nFETs have same  $\beta_n$ .



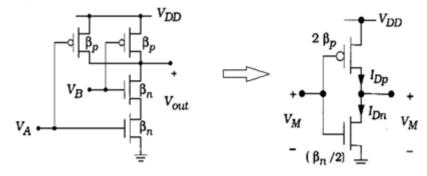
NAND2 logic circuit



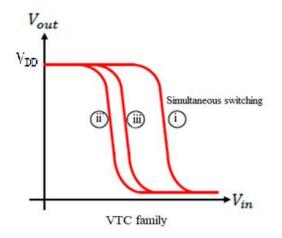
NAND2 Layout



Transition Table



Simplified  $V_M$  circuit for the NAND2 gate (Simultaneous switching)



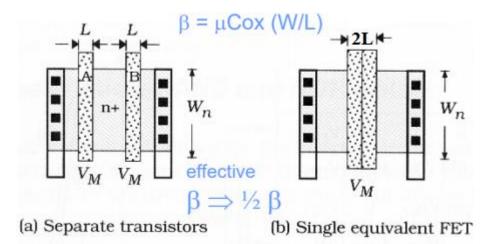
### **DC Characteristics – NAND Gate**



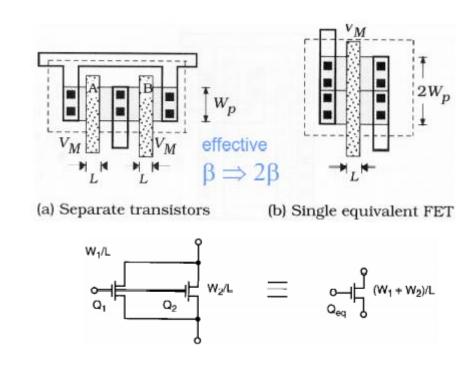
#### • Series/Parallel Equivalent Circuits-

➤ Inputs must be at the same value/voltage

Series transistors – increases effective length



#### Parallel transistors – increases effective width



## **DC Characteristics – NAND Gate**



#### Midpoint voltage for simultaneous switching condition-

- $V_M (V_{in} = V_{out} = V_M)$ 
  - nFET network:  $\frac{\beta_n}{2}$
  - pFET network: 2β<sub>p</sub>
- Both nFET and pFET are in saturation region

$$I_{DSn} = \frac{(\frac{\beta_n}{2})}{2} (V_M - V_{Tn})^2$$
 $I_{SDp} = \frac{(2\beta_p)}{2} (V_{DD} - V_M - |V_{Tp}|)^2$ 
Solve  $I_{DSn} = I_{SDp}$ 

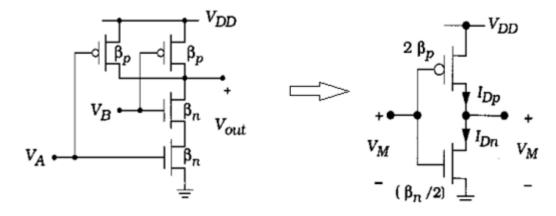
$$\frac{\left(\frac{\beta_{n}}{a}\right)}{\beta} \left(V_{m} - V_{Tn}\right)^{2} = \frac{\left(\frac{a\beta_{p}}{\beta_{p}}\right)}{a^{2}} \left(V_{DD} - V_{m} - |V_{Tp}|\right)^{2}$$

$$\Rightarrow \frac{1}{4} \frac{\beta_{n}}{\beta_{p}} \left(V_{m} - V_{Tn}\right)^{2} = \left(V_{DD} - V_{m} - |V_{Tp}|\right)^{2}$$

$$Taking \quad Square \quad rast -$$

$$\Rightarrow \frac{1}{2} \sqrt{\frac{\beta_{n}}{\beta_{p}}} \left(V_{m} - V_{Tn}\right) = \left(V_{DD} - V_{m} - |V_{Tp}|\right)$$

$$\Rightarrow V_{m} \left(1 + \frac{1}{2} \sqrt{\frac{\beta_{n}}{\beta_{p}}}\right) = V_{DD} - |V_{Tp}| + \frac{1}{2} \sqrt{\frac{\beta_{n}}{\beta_{p}}} V_{Tn}$$



Simplified V<sub>M</sub> circuit for the NAND2 gate (Simultaneous switching)

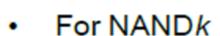


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VISHWA VIDYAPEETHAM
U N I V E R S I T Y
Established u/s 3 of UGC Act 1956

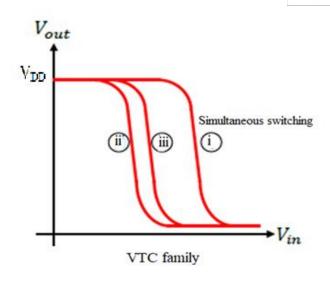
For 2-Input NAND Gate

$$V_{M} = \frac{V_{DD} - |V_{Tp}| + \frac{1}{2} V_{Tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + \frac{1}{2} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$

For Inverter- 
$$V_{M} = \frac{VDD - \left|V_{tp}\right| + V_{tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + \sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$



$$V_{M} = \frac{V_{DD} - \left|V_{Tp}\right| + \frac{1}{k} V_{Tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + \frac{1}{k} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$

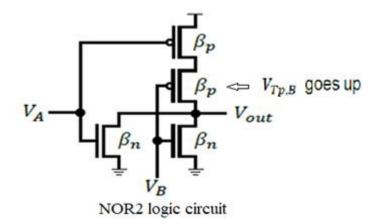


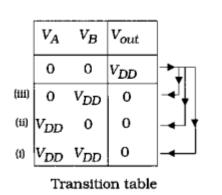


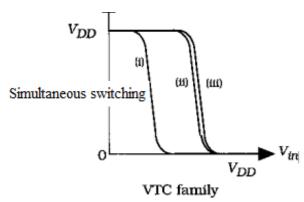
# VISHWA VIDYAPEETHAM UNIVERSITY States and single

#### • NOR Analysis

 $\triangleright$  Both the pFETs are described by  $\beta_p$  and both nFETs have same  $\beta_n$ .







- The substrate Fermi potential φF is negative in NMOS, positive in pMOS
- The substrate bias coefficient γ is positive in nMOS, negative in pMOS
- For pFET-

$$V_{TP} = V_{TP} \left( V_{SB} = 0 \right) - \gamma_p \left( \sqrt{2\phi_n - V_{SB}} - \sqrt{2\phi_n} \right)$$

## **DC Characteristics – NOR Gate**



#### Midpoint voltage for simultaneous switching condition-

- $V_M$  ( $V_{in} = V_{out} = V_M$ )

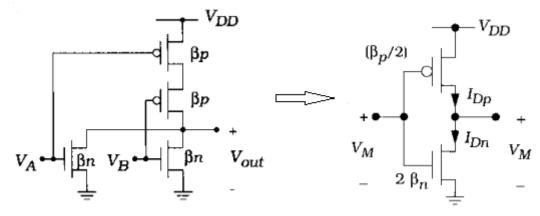
   nFET network:  $2\beta_n$  pFET network:  $\frac{\beta_p}{2}$
- Both nFET and pFET are in saturation region

$$\begin{split} I_{DSn} &= \frac{2\beta_n}{2} (V_M - V_{Tn})^2 \\ I_{SDp} &= \frac{(\frac{\beta_p}{2})}{2} (V_{DD} - V_M - |V_{Tp}|)^2 \\ \text{Solve } I_{DSn} &= I_{SDp}. \end{split}$$

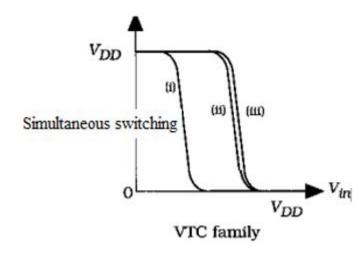
$$V_{M} = \frac{V_{DD} - |V_{Tp}| + 2V_{Tn} \sqrt{\frac{\beta_{R}}{\beta_{p}}}}{1 + 2\sqrt{\frac{\beta_{R}}{\beta_{p}}}}$$

For NORk

$$- V_{M} = \frac{V_{DD} - |V_{Tp}| + kV_{Tn} \sqrt{\frac{\beta_{n}}{\beta_{p}}}}{1 + k\sqrt{\frac{\beta_{n}}{\beta_{p}}}}$$



Simplified V<sub>M</sub> circuit for the NOR2 gate (Simultaneous switching)



# **Assignment-3**



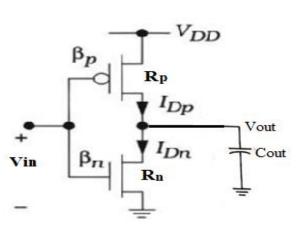
- 1. A CMOS NAND2 is designed using identical nFETs with a value of  $\beta_n = 2\beta_p$ ; the pFETs are the same size. The power supply is chosen to be
  - $V_{DD}$  = 5 V and the device threshold voltages are given as  $V_{Tn}$  = 0.6 V and  $V_{Tp}$  = -0.7 V.
  - (a) Find the midpoint voltage  $V_M$  for the case of simultaneous switching. (2.77 V)
  - (b) What would be the midpoint voltage for an inverter made with the same  $\beta$  specifications? (2.13 V)
- 2. A CMOS NOR2 gate is designed using nFETs with a value of  $\beta_{n.}$  The pFETs are both described by  $\beta_{p}$  = 2.2  $\beta_{n.}$  Find the value of  $V_{M}$  for the case of simultaneous switching if  $V_{DD}$  = 3.3 V,  $V_{Tn}$  = 0.65 V and  $V_{Tp}$  = -0.80 V. (1.47 V)
- 3. A NAND3 gate uses identical nFETs with an aspect ratio of 4. The nFET process transconductance is  $120 \,\mu\text{A/V}^2$ , and the threshold voltage is  $0.55 \,\text{V}$ . A power supply of  $5 \,\text{V}$  is chosen for the circuit.

Find the value of the pFET  $\beta_p$  needed to create a gate where the case of simultaneous switching gives a midpoint voltage of  $V_M = 2.4$  V, Assume that  $V_{Tp} = -0.90$  V and r = 2.4. (63.16  $\mu$ A/V<sup>2</sup>)

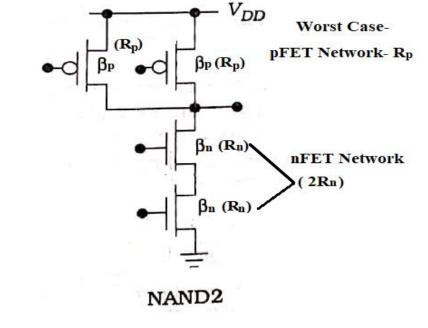


## Why Logic Gate Sizing?

- ➤ High Speed Circuits are limited by the switching time of individual gates.
- ➤ Aspect Ratios Critical Design Parameters for both DC and transient switching times.
- Inverter is used as a reference and then attempt to design other gates that have approximately the same switching times.



$$t_{r} = 2.2 R_{p} C_{out}$$
 
$$t_{f} = 2.2 R_{n} C_{out}$$
 
$$t_{f} \alpha R_{n}$$
 
$$t_{f} \alpha R_{n}$$







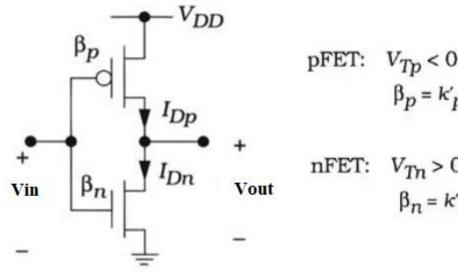
#### Non Symmetrical Inverter

 $\triangleright$  A non Symmetrical Inverter uses equal size of transistor. Where  $\beta n > \beta p$ 

$$(W/L)_n = (W/L)_p$$
  
 $C_{OXn} = C_{OXp}$  (always)

$$\frac{\beta_n}{\beta_p} = \frac{\mu_n C_{oxn} \left(\frac{W}{L}\right)_n}{\mu_p C_{oxp} \left(\frac{W}{L}\right)_p} = \frac{\mu_n}{\mu_p} \cong 2or3$$

$$\frac{k'_n}{k'_p} = \frac{\mu_n}{\mu_p} = r = \text{mobility ratio}$$



$$\beta_p = k'_p \left(\frac{w}{L}\right)_p$$

nFET: 
$$V_{Tn} > 0$$
  
 $\beta_n = \kappa'_n \left(\frac{W}{L}\right)_n$ 



### • Symmetrical Inverter

Generally Symmetrical Inverter (Unit Size Inverter) is used as a sizing reference in designing any logic function.

For Symmetrical Inverter

$$\beta_n = \beta_p$$

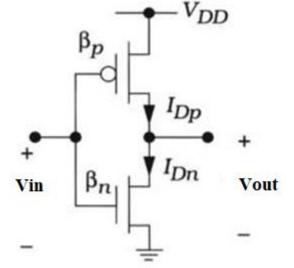
That requires, Vtn = |Vtp| and

$$\left(\frac{W}{L}\right)_p = r\left(\frac{W}{L}\right)_n$$

$$r = \frac{k'_n}{k'_p}$$
 Where K' =  $\mu$  Cox

$$R_n = R_p \Longrightarrow t_r = t_f$$

$$R_p = \frac{1}{\beta_p(V_{DD} - |V_{Tp}|)},$$



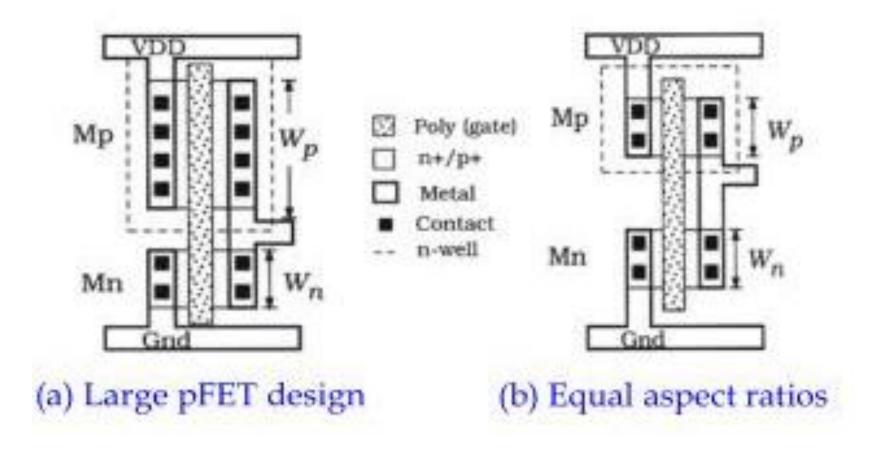
pFET: 
$$V_{Tp} < 0$$
  
 $\beta_p = k'_p \left(\frac{W}{L}\right)_p$ 

nFET: 
$$V_{Tn} > 0$$
  
 $\beta_n = \kappa'_n \left(\frac{W}{L}\right)_n$ 

$$R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})}$$



• Identify Symmetrical and Non Symmetrical CMOS Inverter





## Symmetrical NAND2 Sizing

- Consider parallel pFETS- Worst case  $\beta_P = \beta_p$
- ➤ Series-connected nFETs-

$$R = R_N + R_N$$
 where  $R_N = \frac{1}{\beta_N (V_{DD} - V_{Tn})}$ 

Using the inverter as a reference, we set

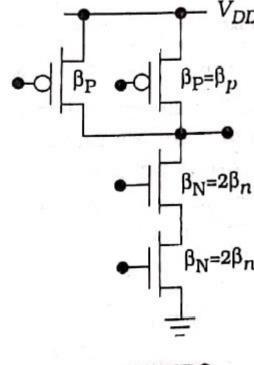
$$R = R_n = 2R_N$$

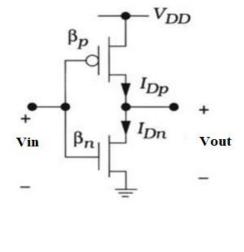
Substituting,

$$\frac{1}{\beta_n(V_{DD} - V_{Tn})} = \frac{2}{\beta_N(V_{DD} - V_{Tn})}$$

which has the solution

$$\dot{\beta}_{N} = 2\beta_{n}$$







## Symmetrical NOR2 Sizing

For parallel nFETs- worst case

$$\beta_N = \beta_n$$

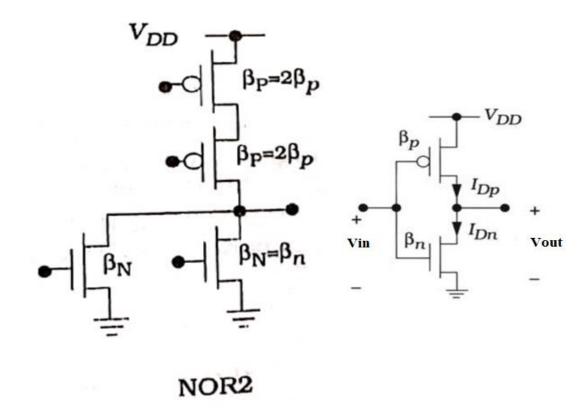
For series connected pFETs-

$$R = R_p = 2R_p$$

$$\frac{1}{\beta_p(V_{DD} - |V_{Tp}|)} = \frac{2}{\beta_p(V_{DD} - |V_{Tp}|)}$$

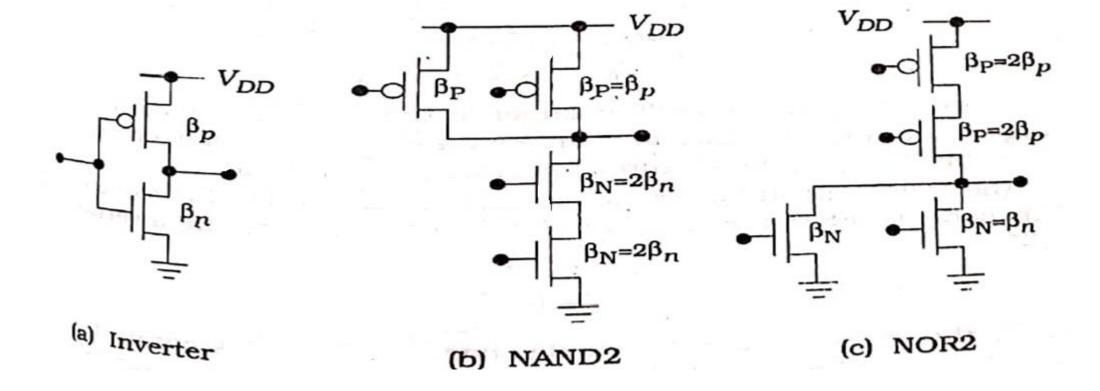
$$\beta_P = 2\beta_p$$

$$\left(\frac{W}{L}\right)_{P} = 2\left(\frac{W}{L}\right)_{p}$$



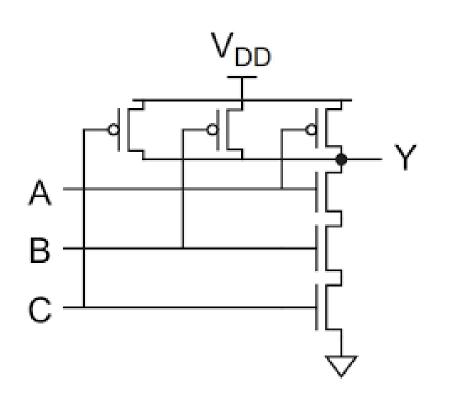


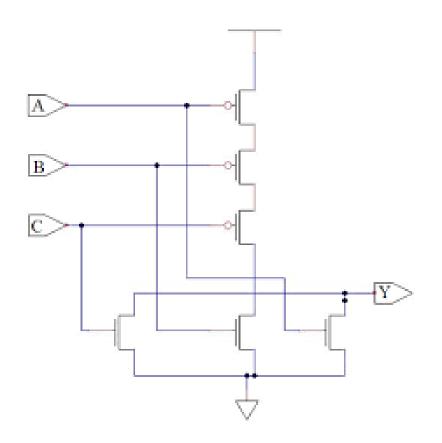
#### Summary





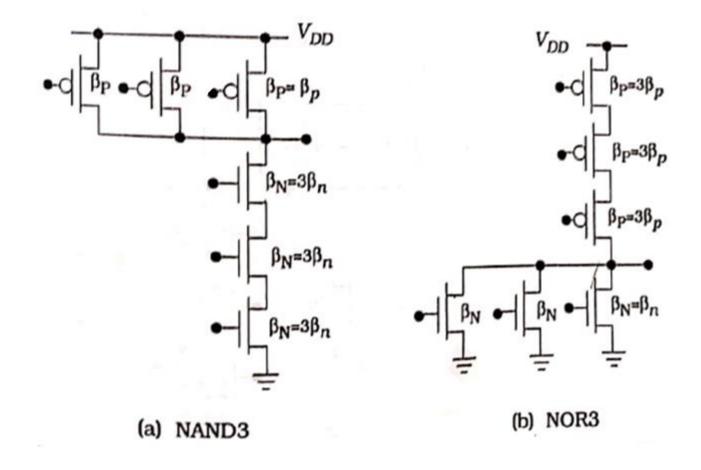
• Sizing of 3-Input gates







#### • Answer-





#### Sizing of Complex function

A CMOS logic gate that implements the function

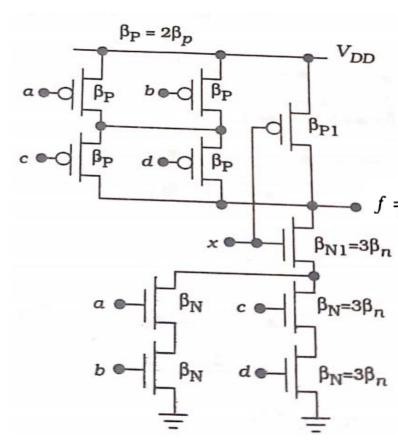
$$f = \overline{(a \cdot b + c \cdot d) \cdot x}$$

- (a) Design the logic circuit.
- (b) An inverter with  $\beta_n = \beta_p$  is used as sizing reference. Find the device sizes needed to equalize the nFET and pFET resistances.

Ans. 
$$\beta_{N} = \beta_{N1} = 3 \beta_{n} = 3\beta_{p}$$
$$\beta_{P} = 2\beta_{p}$$
$$\beta_{P1} = 2\beta_{p} \text{ or } \beta_{p}$$

(c) An inverter with  $\beta_n = 1.5\beta_p$  is used as sizing reference. Find the device sizes needed to equalize the nFET and pFET resistances.

Ans. 
$$\beta_{N} = \beta_{N1} = 3 \ \beta_{n} = 4.5\beta_{p}$$
$$\beta_{P} = 2\beta_{p}$$
$$\beta_{P1} = 2\beta_{p} \text{ or } \beta_{p}$$



 $\beta_{P1} = 2 \beta p$  or  $\beta p$ Selecting 2  $\beta p$  leads to simpler layout since only a single size P+ diffusion layer would be used.

$$= \overline{(a \cdot b + c \cdot d) \cdot x}$$



# **Assignment-4**

1. A CMOS logic gate that implements the function

$$F = \overline{x \cdot (y + z) + x \cdot w}$$

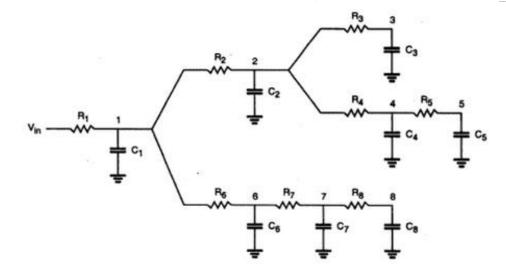
- (a) Design the logic circuit.
- (b) An inverter with  $\beta_n = \beta_p$  is used as sizing reference. Find the device sizes needed to equalize the nFET and pFET resistances.
- 2. A CMOS logic gate that implements the function

$$F = \overline{(a+b).(b+c).d}$$

- (a) Design the logic circuit.
- (b) An inverter with  $\beta_n = 1.5 \ \beta_p$  is used as sizing reference. Find the device sizes needed to equalize the nFET and pFET resistances.



- Consider a general RC tree network,
  - i) There are no resistor loops in this circuit
  - ii) All of the capacitors in an RC tree are connected between a node and the ground
  - iii) There is one input node in the circuit. Also notice that there is a unique resistive path, from the input node to any other node in the circuit.

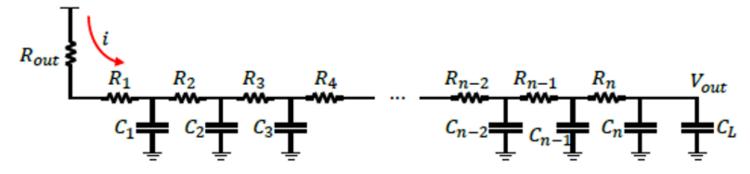


- Inspecting the general topology of this RC tree network, we can make the following path definition:
  - $\triangleright$  Let Pi denote the unique path from the input node to node i, i = 1,2,3,....,N
  - Let  $Pij = Pi \Omega Pj$  denote the portion of the path between the input and the node i, which is common to the path between the input and node j.
  - $\triangleright$  Assuming that the input signal is a step pulse at time t=0, the Elmore delay at node i of this RC tree is given by the following expression.

$$\tau_{Di} = \sum_{j=1}^{N} Cj \sum_{for\ all\ k \in Pij} Rk$$



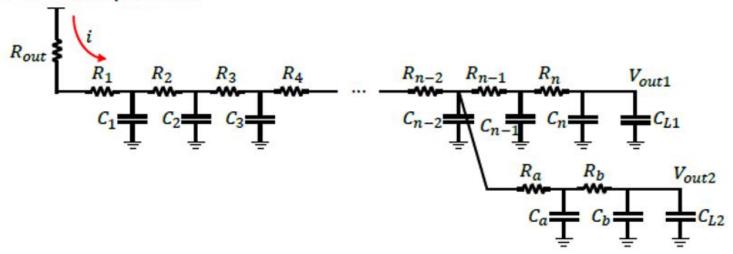
- How to estimate delay in general RC networks.
  - How to
    - Start at the target sink node.
    - Traverse the RC network toward the source.
    - Whenever there is a resistor, multiply its resistance and its downstream capacitance and add it to the total delay.
  - For two-pin nets



$$\tau = R_n(C_n + C_L) + R_{n-1}(C_{n-1} + C_n + C_L) + R_{n-2}(C_{n-2} + C_{n-1} + C_n + C_L) + R_3(C_3 + \dots + C_n + C_L) + R_2(C_2 + \dots + C_n + C_L) + R_1(C_1 + \dots + C_n + C_L) + R_{out}(C_1 + \dots + C_n + C_L)$$



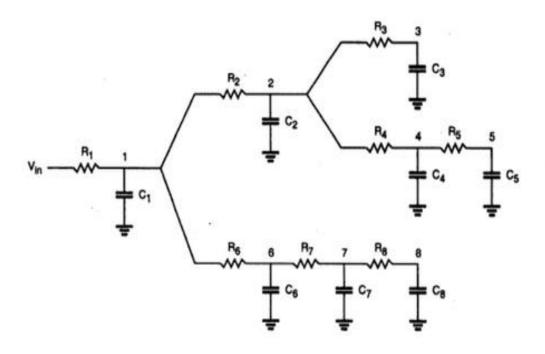
- How to estimate delay in general RC networks.
  - For multi-pin nets



$$\tau(V_{out1}) = R_n(C_n + C_{L1}) + R_{n-1}(C_{n-1} + C_n + C_{L1}) + R_{n-2}(C_{n-2} + C_{n-1} + C_n + C_{L1} + C_a + C_b + C_{L2}) + \dots + R_3(C_3 + \dots + C_n + C_{L1} + C_a + C_b + C_{L2}) + R_2(C_2 + \dots + C_n + C_{L1} + C_a + C_b + C_{L2}) + R_1(C_1 + \dots + C_n + C_{L1} + C_a + C_b + C_{L2}) + R_{out}(C_1 + \dots + C_n + C_{L1} + C_a + C_b + C_{L2})$$

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#### Example



Elmore Delay at node 7 can be calculated as

$$\tau_{D7} = R_7(C_7 + C_8) + R_6(C_6 + C_7 + C_8) + R_1(C_1 + C_2 + C_3 + C_4 + C_5 + C_6 + C_7 + C_8)$$

$$\tau_{D7} = R_1 C_1 + R_1 C_2 + R_1 C_3 + R_1 C_4 + R_1 C_5 + (R_1 + R_6) C_6 + (R_1 + R_6 + R_7) C_7 + (R_1 + R_6 + R_7) C_8$$

Elmore Delay at node 5 can be calculated as

$$\tau_{D5} = R_5 C_5 + R_4 (C_4 + C_5) + R_2 (C_2 + C_3 + C_4 + C_5) + R_1 (C_1 + C_2 + C_3 + C_4 + C_5) + R_2 (C_2 + C_7 + C_8)$$

$$\tau_{D5} = R_1 C_1 + (R_1 + R_2) C_2 + (R_1 + R_2) C_3 + (R_1 + R_2 + R_4) C_4$$

$$+ (R_1 + R_2 + R_4 + R_5) C_5 + R_1 C_6 + R_1 C_7 + R_1 C_8$$



#### • Example

Assume N = 8 and solve if R1 = R2 = .... = R8 = 1 K Ohm, and C1 = C2 = .... = C8 = 2 pF. Find delay at node 8.

